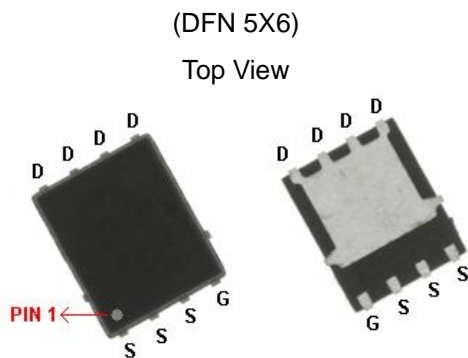


N-Channel 30V (D-S) MOSFET, ESD Protected

GENERAL DESCRIPTION

The ME7890D-G is the N-Channel logic enhancement mode power field effect transistors are produced using high cell density , DMOS trench technology. This high density process is especially tailored to minimize on-state resistance. These devices are particularly suited for low voltage application such as cellular phone and notebook computer power management and other battery powered circuits where Low-side switching , and low in-line power loss are needed in a very small outline surface mount package.

PIN CONFIGURATION



Ordering Information: ME7890D (Pb-free)

ME7890D-G (Green product-Halogen free)

Absolute Maximum Ratings (TA=25°C Unless Otherwise Noted)

Parameter	Symbol	Maximum Ratings	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current*	I _D	TA=25°C	19
		TA=70°C	15
Pulsed Drain Current	I _{DM}	78	A
Maximum Power Dissipation*	P _D	TA=25°C	2.7
		TA=70°C	1.7
Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C
Thermal Resistance-Junction to Ambient*	R _{θJA}	45	°C/W

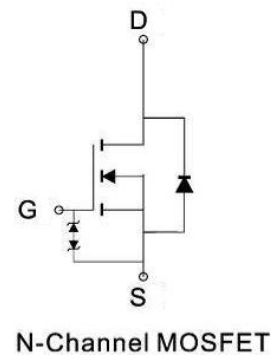
*The device mounted on 1in² FR4 board with 2 oz copper

FEATURES

- R_{DS(ON)} ≤ 4.6mΩ@V_{GS}=10V
- R_{DS(ON)} ≤ 7.8mΩ@V_{GS}=4.5V
- Super high density cell design for extremely low R_{DS(ON)}
- Exceptional on-resistance and maximum DC current capability

APPLICATIONS

- Portable Equipment
- Battery Powered System
- DC/DC Converter
- Load Switch



N-Channel 30V (D-S) MOSFET, ESD Protected

Electrical Characteristics (TA=25°C Unless Otherwise Specified)

Symbol	Parameter	Limit	Min	Typ	Max	Unit
STATIC						
V _{(BR)DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250 μA	30			V
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250 μA	1.0		3.0	V
I _{GSS}	Gate Leakage Current	V _{DS} =0V, V _{GS} =±16V			±10	μA
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V			1	μA
R _{DS(ON)}	Drain-Source On-State Resistance ^a	V _{GS} =10V, I _D =20A		3.8	4.6	mΩ
		V _{GS} =4.5V, I _D =16A		6	7.8	
V _{SD}	Diode Forward Voltage	I _S =1.0A, V _{GS} =0V		0.7	1.2	V
DYNAMIC						
Q _g	Total Gate Charge	V _{DS} =15V, V _{GS} =10V, I _D =20A		54		nC
Q _g	Total Gate Charge	V _{DS} =15V, V _{GS} =4.5V, I _D =20A		27		
Q _{gs}	Gate-Source Charge			9.5		
Q _{gd}	Gate-Drain Charge			11		
C _{iss}	Input Capacitance	V _{DS} =15V, V _{GS} =0V, F=1MHz		2450		pF
C _{oss}	Output Capacitance			393		
C _{rss}	Reverse Transfer Capacitance			129		
t _{d(on)}	Turn-On Delay Time	V _{DD} =15V, R _L =15Ω V _{GEN} =10V, R _G =3Ω		23		ns
t _r	Turn-On Rise Time			16		
t _{d(off)}	Turn-Off Delay Time			73		
t _f	Turn-Off Fall Time			12		

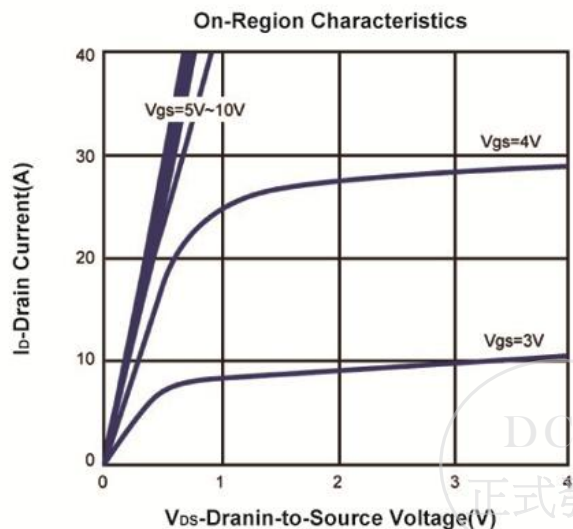
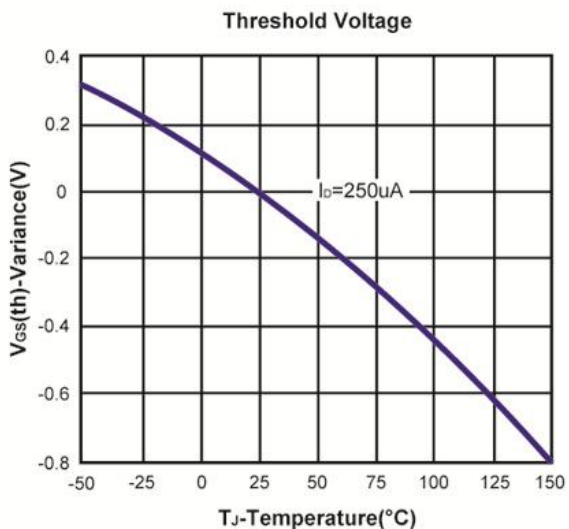
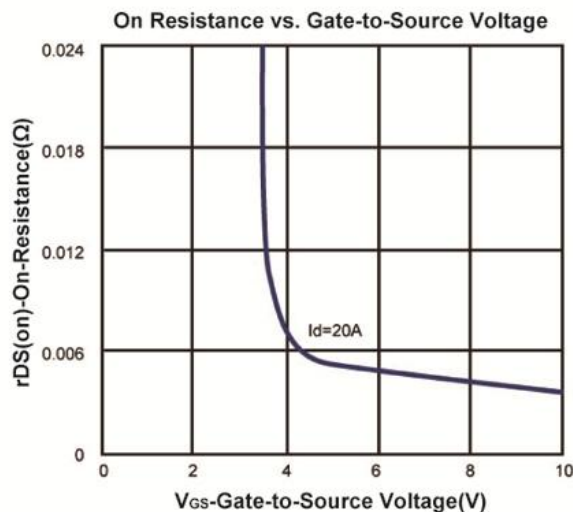
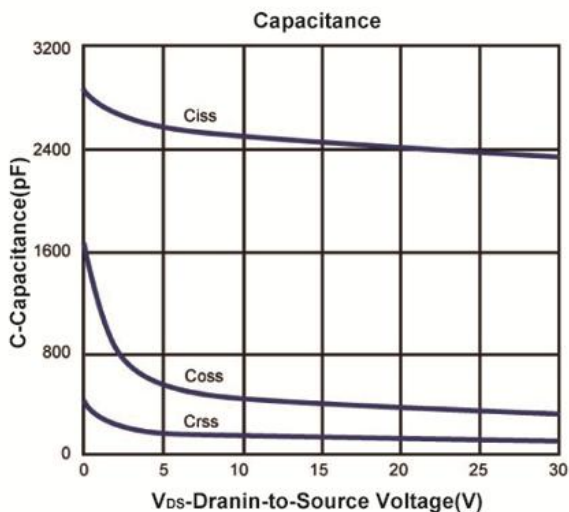
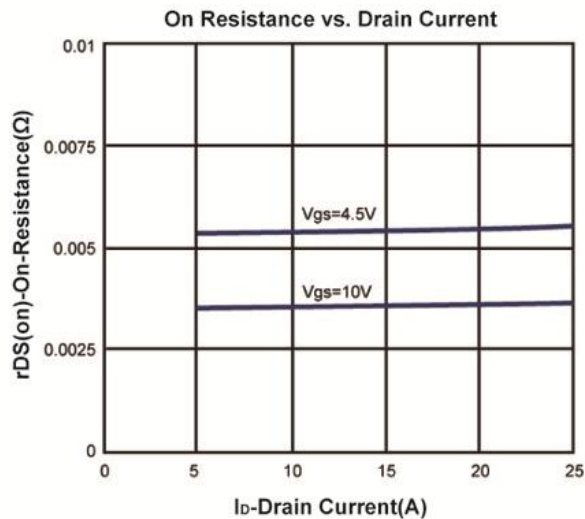
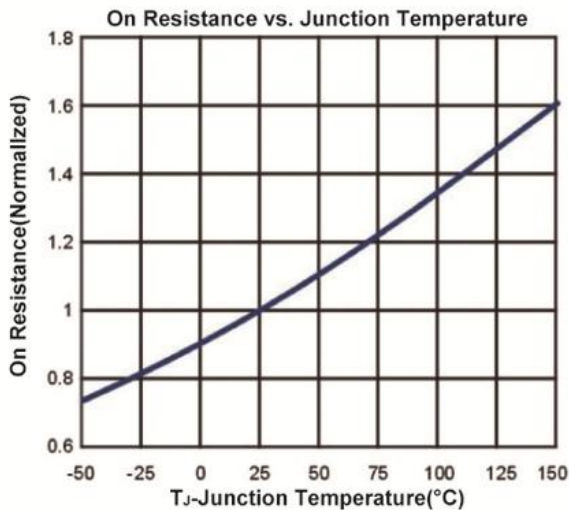
Note: a. Pulse test: pulse width ≤ 300us, duty cycle ≤ 2%, Guaranteed by design, not subject to production testing.

b. Matsuki Electric/ Force mos reserves the right to improve product design, functions and reliability without notice.



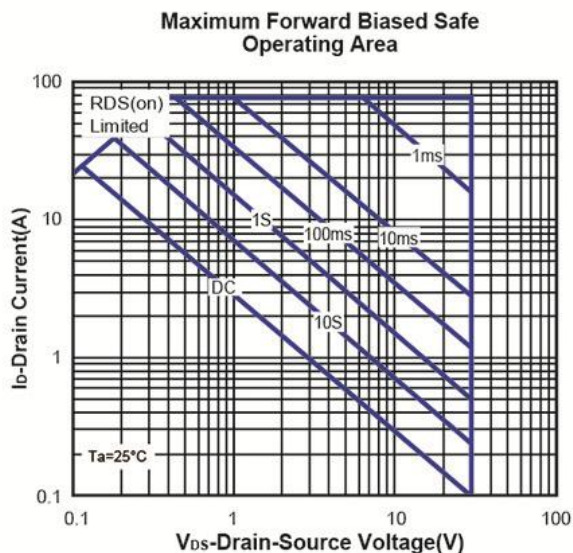
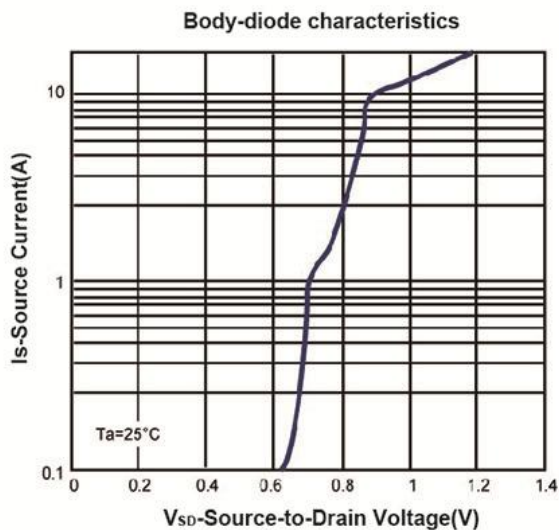
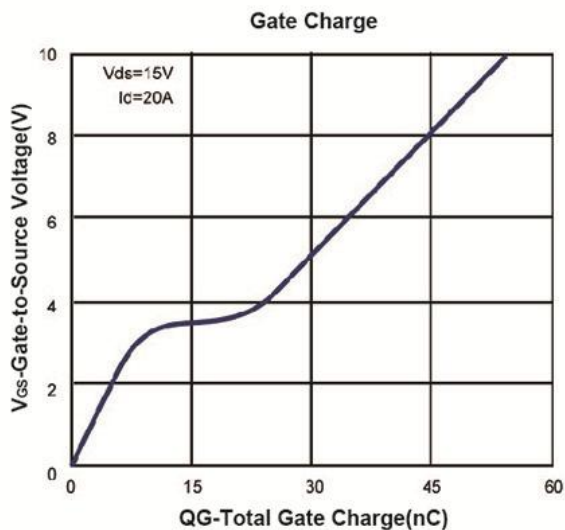
N-Channel 30V (D-S) MOSFET, ESD Protected

Typical Characteristics (T_J = 25°C Noted)

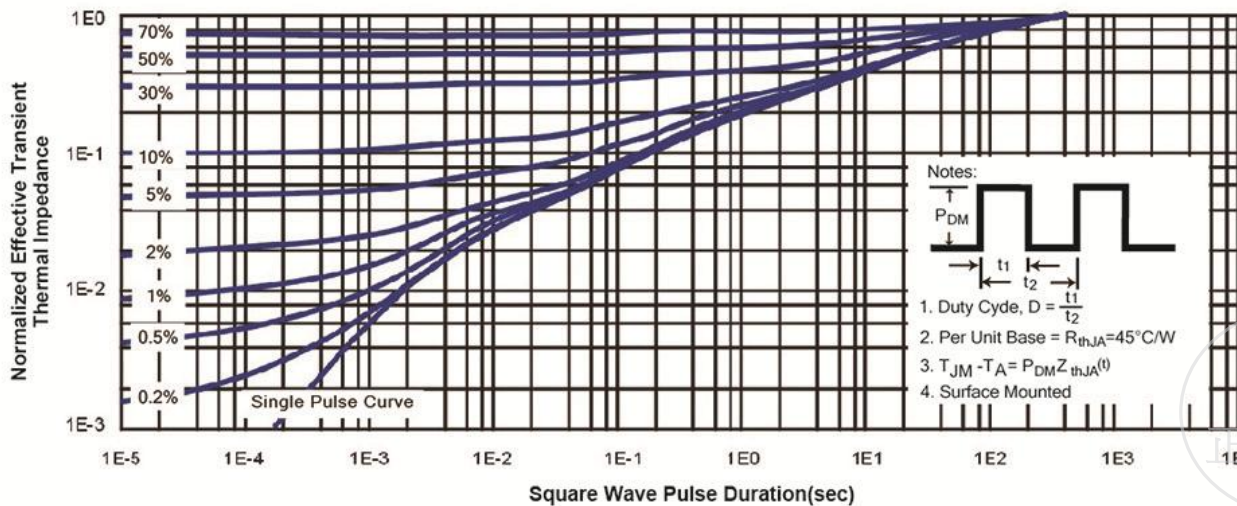


N-Channel 30V (D-S) MOSFET, ESD Protected

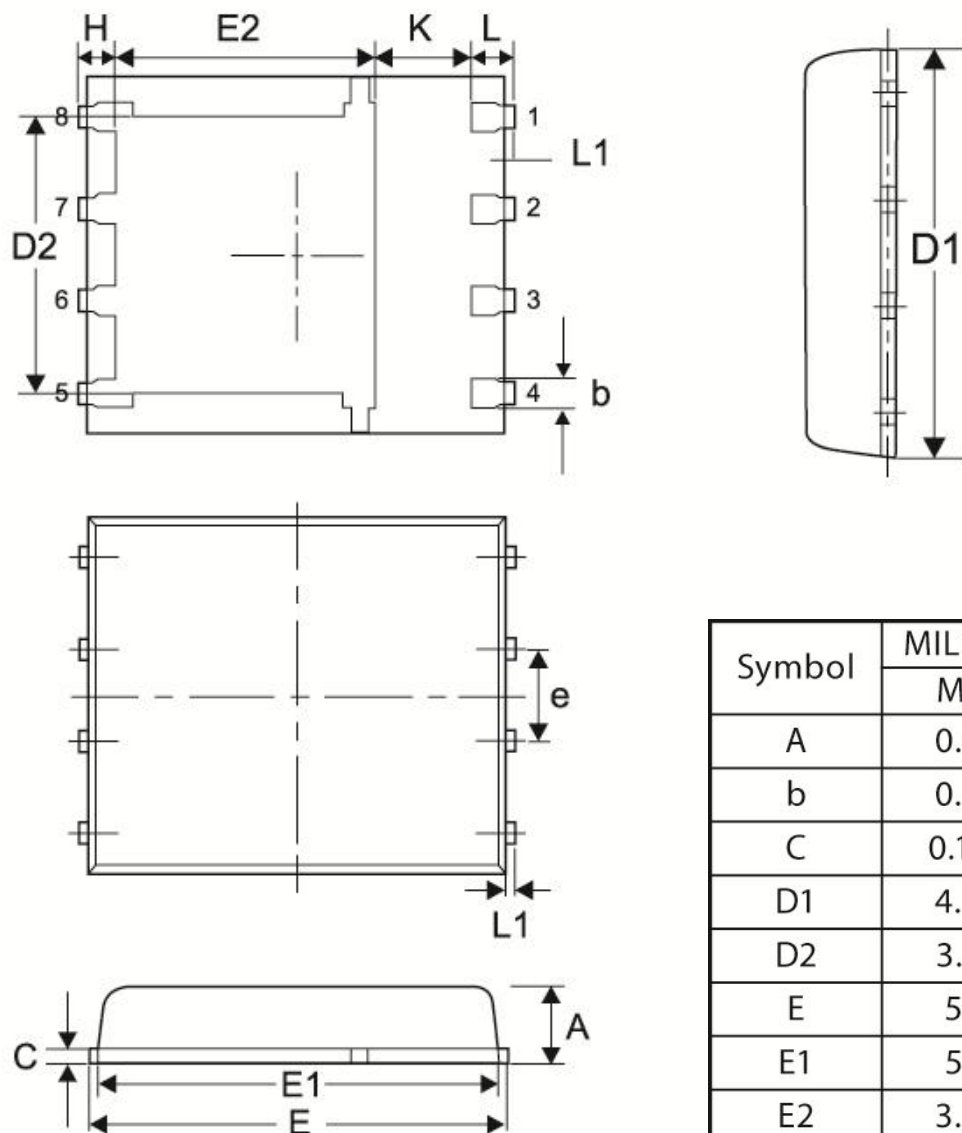
Typical Characteristics (T_J =25°C Noted)



Normalized Thermal Transient Impedance, Junction-to-Ambient



DFN 5X6 Package Outline



Symbol	MILLIMETERS (mm)	
	MIN	MAX
A	0.90	1.25
b	0.33	0.51
C	0.155	0.30
D1	4.80	5.00
D2	3.61	3.96
E	5.8	6.20
E1	5.6	5.90
E2	3.35	4.31
e	1.27 BSC	
H	0.35	0.61
K	1.60	-
L	0.35	0.71
L1	0.05	0.20

